SLOVENSKI STANDARD

SIST EN 61967-5:2005

december 2005

Integrirana vezja – Meritve elektromagnetnega sevanja, od 150 kHz do 1 GHz – 5. del: Meritve prevajanega sevanja – Metoda z namizno Faradayevo kletko (IEC 61967-5:2003)

Integrated circuits – Measurement of electromagnetic emissions, 150 kHz to 1 GHz – Part 5: Measurement of conducted emissions – Workbench Faraday Cage method (IEC 61967-5:2003)

ICS 31.200

Referenčna številka
SIST EN 61967-5:2005(en)

EUROPEAN STANDARD **EN 61967-5**

NORME EUROPÉENNE

EUROPÄISCHE NORM April 2003

ICS 31.200

English version

Integrated circuits – Measurement of electromagnetic emissions, 150 kHz to 1 GHz Part 5: Measurement of conducted emissions – Workbench Faraday Cage method

(IEC 61967-5:2003)

Circuits intégrés -
Mesure des émissions électromagnétiques, 150 kHz à 1 GHz
Partie 5: Mesure des émissions conduites - Méthode de la cage de Faraday sur banc de travail
(CEI 61967-5:2003)

Integrierte Schaltungen – Messung von elektromagnetischen Aussendungen im Frequenzbereich von 150 kHz bis 1 GHz
Teil 5: Messung der leitungsgeführten Aussendungen – Verfahren mit Faradayschem Käfig für Messtische
(IEC 61967-5:2003)

This European Standard was approved by CENELEC on 2003-04-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Luxembourg, Malta, Netherlands, Norway, Portugal, Slovakia, Spain, Sweden, Switzerland and United Kingdom.

CENELEC
European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Ref. No. EN 61967-5:2003 E

Foreword

The text of document 47A/661/FDIS, future edition 1 of IEC 61967-5, prepared by SC 47A, Integrated circuits, of IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61967-5 on 2003-04-01.

This part of EN 61967 is to be read in conjunction with EN 61967-1:2002.

The following dates were fixed:

– latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2004-01-01

– latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2006-04-01

Annexes designated "normative" are part of the body of the standard.
Annexes designated "informative" are given for information only.
In this standard, annexes A and ZA are normative and annexes B, C and D are informative.
Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 61967-5:2003 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61967-4	NOTE	Harmonized as EN 61967-4:2002 (not modified).
IEC 61967-6	NOTE	Harmonized as EN 61967-6:2002 (not modified).

Annex ZA
(normative)

Normative references to international publications with their corresponding European publications

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

Publication	Year	Title	EN/HD	Year
IEC 60050-131	2002	International Electrotechnical Vocabulary Part 131: Circuit theory	-	-
IEC 60050-161	1990	Chapter 161: Electromagnetic compatibility	-	-
IEC 61967-1	2002	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz Part 1: General conditions and definitions	EN 61967-1	2002
IEC 61000-4-6	1996	Electromagnetic compatibility (EMC) Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields	EN 61000-4-6	1996

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Circuits intégrés – Mesure des émissions électromagnétiques, 150 kHz à 1 GHz –

Partie 5: Mesure des émissions conduites – Méthode de la cage de Faraday sur banc de travail

Integrated circuits – Measurement of electromagnetic emissions, 150 kHz to 1 GHz –

Part 5: Measurement of conducted emissions – Workbench Faraday Cage method

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International Electrotechnical Commission
Международная Электротехническая Комиссия

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC EMISSIONS, 150 kHz TO 1 GHz –

Part 5: Measurement of conducted emissions – Workbench Faraday Cage method

FOREWORD

1) The IEC (International Electrotechnical Commission) is a worldwide organisation for standardisation comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardisation in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organisations liasing with the IEC also participate in this preparation. The IEC collaborates closely with the International Organisation for Standardisation (ISO) in accordance with conditions determined by agreement between the two organisations.

2) The formal decisions or agreements of the IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested National Committees.

3) The documents produced have the form of recommendations for international use and are published in the form of standards, technical specifications, technical reports or guides and they are accepted by the National Committees in that sense.

4) In order to promote international unification, IEC National Committees undertake to apply IEC International Standards transparently to the maximum extent possible in their national and regional standards. Any divergence between the IEC Standard and the corresponding national or regional standard shall be clearly indicated in the latter.

5) The IEC provides no marking procedure to indicate its approval and cannot be rendered responsible for any equipment declared to be in conformity with one of its standards.

6) Attention is drawn to the possibility that some of the elements of this International Standard may be the subject of patent rights. The IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 61967-5 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47A/661/FDIS	47A/664/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 61967 is to be read in conjunction with IEC 61967-1.

IEC 61967 consists of the following parts, under the general title *Integrated circuits – Measurement of electromagnetic emissions, 150 kHz to 1 GHz*:

Part 1: General conditions and definitions

Part 2: Measurement of radiated emissions – TEM-cell method [1]

Part 3: Measurement of radiated emissions – Surface scan method [2]

Part 4: Measurement of conducted emissions – 1 Ω/150 Ω direct coupling method

Part 5: Measurement of conducted emissions – Workbench Faraday Cage method

Part 6: Measurement of conducted emissions – Magnetic probe method

The committee has decided that the contents of this publication will remain unchanged until 2008. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

[1] Under consideration.

[2] Under consideration.

INTRODUCTION

IEC 61967-1 provides general information and definitions on measurement of conducted and radiated electromagnetic emissions from integrated circuits. It also provides a description of measurement conditions, test equipment and set-up as well as the test procedures and content of the test reports.